

FORM PTO-1449	ATTY. DKT NO.	01-279-CON	SER. NO.	10/187164
	APPLICANT	TESHIMA		
	FILING DATE	February 27, 2004	GROUP	2826

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>pn</i>	S/N 09/489,475	Jan. 21, 2000	Kimura et al.		
	S/N 09/675,209	Sept. 29, 2000	Suzuki et al.		
	S/N 09/351,458	July 12, 1999	Nakase		
	S/N 09/435,840	Nov. 8, 1999	Hirai		
	S/N 09/717,227	Nov. 22, 2000	Mamitsu et al.		
	5,641,997	June 24, 1997	Ohta et al.		
	5,789,820	Aug. 4, 1998	Yamashita		
<i>pn</i>	5,708,299	Jan. 13, 1998	Teramae et al.		

FOREIGN PATENT DOCUMENTS

ABSTRACT

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>pn</i>	JP-A-5-283562 *	10/29/93	JAPAN				X	
	JP-A-6-349987 *	12/22/94	JAPAN				X	
	JP-A-7-45765 *	2/14/95	JAPAN				X	
	JP-A-11-186469 *	7/9/99	JAPAN				X	
	JP-A-2000-31351 *	1/28/00	JAPAN				X	
	JP-A-2001-118961 *	4/27/01	JAPAN				X	
	JP-A-6-291223 *	10/18/94	JAPAN				X	
	JP-A-3-20067 *	1/29/91	JAPAN				X	
	GB 2146174	4/11/85	U.K.				X	
<i>pn</i>	JP-A-4-249353 *	9/4/92	JAPAN				X	

- * Full English text of the JP Document will be available in machine-translated form from JP (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

<i>pn</i>	Nobuhiro Takamura, <u>ELECTRONIC TECHNOLOGY</u> , 1999-5, pp. 56-59.
<i>pn</i>	Johnson and Pote, "Silicon Precipitate Nodule-Induced Failures of MOSFETs," <u>ISTFA '91: The 17th International Symposium for Testing & Failure Analysis</u> , Los Angeles, CA, November 11-15, 1991, pp. 161-165.
EXAMINER	DATE CONSIDERED
<i>alps</i>	6/9/04

FORM PTO-1449	ATTY. DKT NO.	01-279-CON	SER. NO.	101-787/24
	APPLICANT	TESHIMA		
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REFERENCE DESIGNATION

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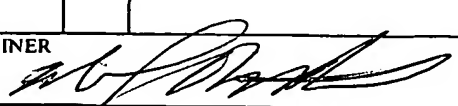
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
pf	6,072,240	June 6, 2000	Kimura et al.		
	5,248,853	Sept. 28, 1993	Ishikawa et al.		
	5,801,445	Sept. 1, 1998	Ishihara et al.		
	5,229,646	July 20, 1993	Tsumura		
	4,558,345	Dec. 10, 1985	Dwyer et al.		
	4,546,374	Oct. 8, 1985	Olsen et al.		
	4,984,061	Jan. 8, 1991	Matsumoto et al.		
OV	5,481,137	Jan. 2, 1996	Harada et al.		

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								ABSTRACT	
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
pf	JP-A-11-260979 *	9/24/99	JAPAN				X		
	JP-A-4-27145 *	1/30/92	JAPAN				X		
	JP-A-9-148492 *	6/6/97	JAPAN				X		
	JP-A-4-12555 *	1/17/92	JAPAN				X		
	JP-A-4-103150 *	4/6/92	JAPAN				X		
	JP-A-60-137042 *	7/20/85	JAPAN				X		
	JP-A-5-109919 *	4/30/93	JAPAN				X		
	JP-A-61-166051 *	7/26/86	JAPAN				X		
	JP-A-2-117157 *	5/1/90	JAPAN				X		
	JP-A-63-102326 *	5/7/88	JAPAN				X		
	JP-A-60-235430 *	11/22/85	JAPAN				X		
	JP-A-7-240432 *	9/12/95	JAPAN				X		
	JP-A-8-45874 *	2/16/96	JAPAN				X		
JP-A-S62-2558	1/8/87	JAPAN				X			
OV	JP-A-2000-294699	10/20/00	JAPAN				X		
	JP-A-H05-267491	10/15/93	JAPAN				X		

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
	6/5/04

FORM PTO-1449	ATTY. DKT NO.	01-279-CON	SER. NO.	101787164
	APPLICANT	TESHIMA		
	FILING DATE	February 27, 2004	GROUP	2825

REFERENCE DESIGNATION

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>mn</i>	4,827,082	May 2, 1989	Horiuchi et al.		
	4,538,170	Aug. 27, 1985	Yerman		
	4,646,129	Feb. 24, 1987	Yerman		
	4,141,030	Feb. 20, 1979	Eisele et al.		
	3,648,121	March, 1972	Suenaga et al.		
	3,818,584	June, 1974	Suenaga et al.		
<i>mn</i>	6,542,365	April, 2003	Inoue		

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ABSTRACT									YES	NO
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS				
<i>mn</i>	JP-A-60-95947 *	5/29/85	JAPAN						X	
	JP-A-61-265849 *	11/25/86	JAPAN						X	
	JP-A-62-141751 *	6/25/87	JAPAN						X	
	JP-A-63-96946 *	4/27/88	JAPAN						X	
	JP-A-62-92349 *	4/27/87	JAPAN						X	
	JP-A-62-287649 *	12/14/87	JAPAN						X	
	JP-B2-59-38734 *	9/19/84	JAPAN						X	
	JP-A-1-228138 *	9/12/89	JAPAN						X	
	JP-A-54-40569 *	3/30/79	JAPAN						X	
	JP-A-61-251043 *	11/8/86	JAPAN						X	
	JP-A-54-95183 *	7/27/79	JAPAN						X	
	JP-A-59-31042 *	2/18/84	JAPAN						X	
	JP-A-7-38013 *	2/7/95	JAPAN						X	
	JP-A-7-273276 *	10/20/95	JAPAN						X	
	JP-A-8-191145 *	7/23/96	JAPAN						X	
<i>mn</i>	JP-A-2000-91485 *	3/31/00	JAPAN						X	

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>mn</i>	DATE CONSIDERED	4/4/04
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FORM PTO-1449	ATTY. DKT NO.	01-279-CON	SER. NO.	10/787164
	APPLICANT	TESHIMA		
	FILING DATE	February 27, 2004	GROUP	2826

REFERENCE DESIGNATION

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>an</i>	4,685,987	Aug. 11, 1987	Fick		
	5,311,060	May 10, 1994	Rostoker et al.		
	5,886,400	Mar. 23, 1999	Letterman, Jr. et al.		
	6,072,240	Jun. 6, 2000	Kimura et al.		
<i>an</i>	2003/0132530 A1	Jul. 17, 2003	Teshima et al.		

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								TRANSLATION	
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS		YES	NO
<i>an</i>	JP-A-S58-34951	3/1/83	JAPAN					X (Abstract)	
<i>an</i>	JP-A-2000-174180	6/23/00	JAPAN					X (Abstract)	

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>[Signature]</i>	DATE CONSIDERED
		6/9/24